

FZ24N-VB Datasheet N-Channel 60 V(D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	60				
R _{DS(on)} (Ω)	V _{GS} = 10 V 0.072				
Q _g max. (nC)	25				
Q _{gs} (nC)	5.8				
Q _{gd} (nC)	11				
Configuration	Single				

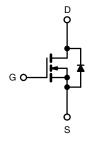
FEATURES

- Dynamic dV/dt rating
- · Fast switching
- Ease of paralleling

Simple drive requirements







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	60	V	
Gate-Source Voltage			V _{GS}	± 20	V	
Continuous Drain Current	V at 10 V	$T_{\rm C} = 25 \ ^{\circ}{\rm C}$ $T_{\rm C} = 100 \ ^{\circ}{\rm C}$	I	20		
Continuous Drain Current	V _{GS} at 10 V	T _C = 100 °C	Ι _D	12	А	
Pulsed Drain Current ^a			I _{DM}	68		
Linear Derating Factor				0.40	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	100	mJ	
Maximum Power Dissipation	T _C = 25 °C		PD	60	W	
Peak Diode Recovery dV/dt ^c			dV/dt	4.5	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +175	°C	
Soldering Recommendations (Peak temperature) ^d	for 10 s			300	7	
Mounting Torque	6 22 or 1			10	lbf ∙ in	
Mounting Torque	6-32 or M3 screw			1.1	N · m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

- b. $V_{DD} = 25 \text{ V}$, starting $T_J = 25 \text{ °C}$, $L = 403 \mu\text{H}$, $R_g = 25 \Omega$, $I_{AS} = 17 \text{ A}$ (see fig. 12). c. $I_{SD} \le 17 \text{ A}$, $dI/dt \le 140 \text{ A/}\mu\text{s}$, $V_{DD} \le V_{DS}$, $T_J \le 175 \text{ °C}$.

d. 1.6 mm from case.





THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	62	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	2.5	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static					•		
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D = 250 μA	60	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I _D = 1 mA	-	0.061	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	· V _{GS} , I _D = 250 μA	1.0	-	3.0	V
Gate-Source Leakage	I _{GSS}		$V_{\rm GS}$ = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I	V _{DS} :	= 60 V, V _{GS} = 0 V	-	-	25	μA
Zero Gale voltage Drain Gurrent	IDSS	V _{DS} = 48 V,	V_{GS} = 0 V, T_J = 150 °C	-	-	250	
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$	I _D = 10 A ^b	-	0.072	-	Ω
Forward Transconductance	9 _{fs}	V _{DS}	= 25 V, I _D = 10 A	5.5	-	-	S
Dynamic							
Input Capacitance	C _{iss}		$V_{GS} = 0 V_{V}$	-	640	-	
Output Capacitance	C _{oss}	$\begin{array}{c c c c c c c c c c c c c c c c c c c $			-	pF	
Reverse Transfer Capacitance	C _{rss}	t = 1.	0 MHz, see fig. 5	-	79	-	1
Total Gate Charge	Qg			-	-	25	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	V $I_D = 17 \text{ A}, V_{DS} = 48 \text{ V},$ see fig. 6 and 13 ^b		-	5.8	nC
Gate-Drain Charge	Q _{gd}		6	-	-	11	1
Turn-On Delay Time	t _{d(on)}			-	13	-	
Rise Time	t _r	$V_{DD} = 30 \text{ V}, \text{ I}_D = 17 \text{ A},$ $\text{R}_\text{g} = 18 \ \Omega, \text{ R}_\text{D} = 1.7 \ \Omega, \text{ see fig. } 10^{\text{ b}}$		-	58	-	- ns
Turn-Off Delay Time	t _{d(off)}			-	25	-	
Fall Time	t _f			-	42	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from		-	4.5	-	
Internal Source Inductance	L _S	package and die contact	package and center of die contact		7.5	-	- nH
Drain-Source Body Diode Characteristic	s						1
Continuous Source-Drain Diode Current	I _S	MOSFET sym showing the	bol	-	-	20	•
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction diode		-	-	68	A
Body Diode Voltage	V _{SD}	$T_{\rm J}$ = 25 °C, $I_{\rm S}$ = 17 A, $V_{\rm GS}$ = 0 V ^b		-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	$T_{J} = 25 \text{ °C}, I_{F} = 17 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}$		-	88	180	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.29	0.64	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time is negligible (turn	-on is doi	minated b	y L _S and	L _D)

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

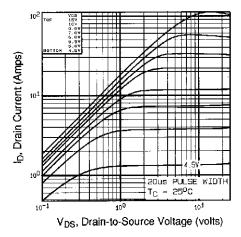


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

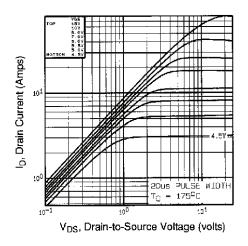


Fig. 2 - Typical Output Characteristics, $T_C = 175 \ ^{\circ}C$

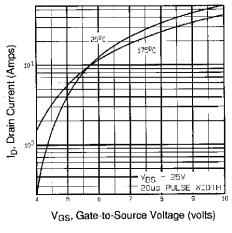


Fig. 3 - Typical Transfer Characteristics

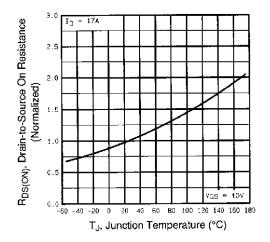


Fig. 4 - Normalized On-Resistance vs. Temperature

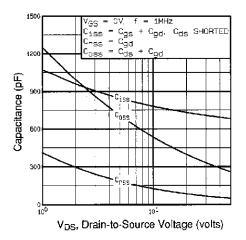


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

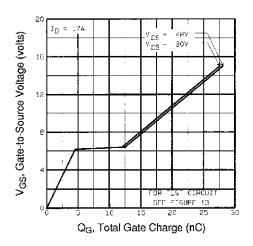


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



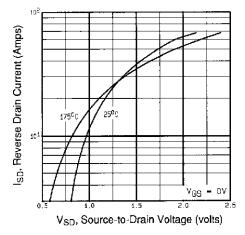


Fig. 7 - Typical Source-Drain Diode Forward Voltage

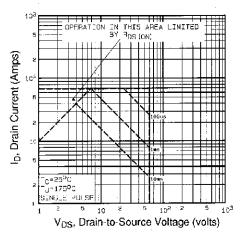


Fig. 8 - Maximum Safe Operating Area

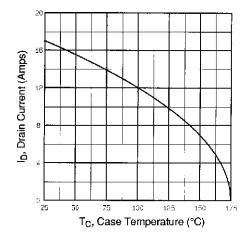


Fig. 9 - Maximum Drain Current vs. Case Temperature

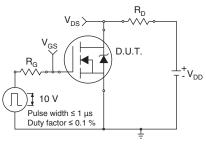


Fig. 10a - Switching Time Test Circuit

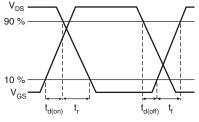
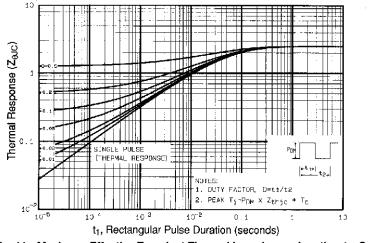


Fig. 10b - Switching Time Waveforms







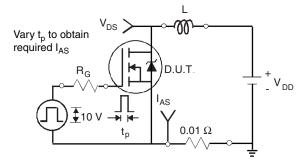


Fig. 12a - Unclamped Inductive Test Circuit

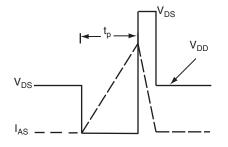


Fig. 12b - Unclamped Inductive Waveforms

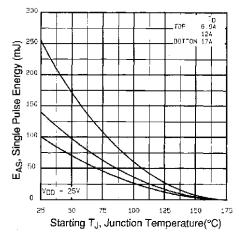


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

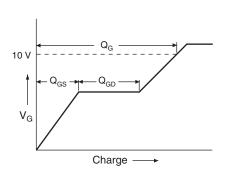


Fig. 13a - Basic Gate Charge Waveform

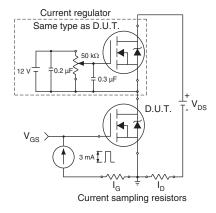
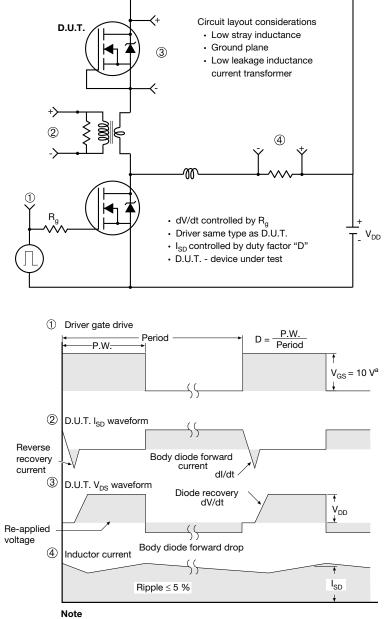


Fig. 13b - Gate Charge Test



Peak Diode Recovery dV/dt Test Circuit

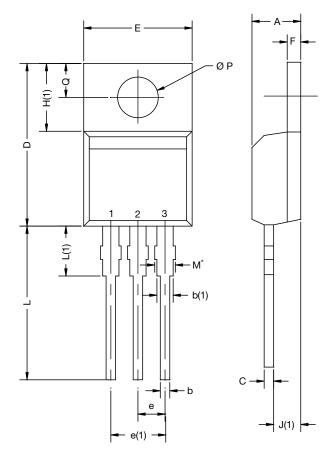


a. $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel



TO-220



DIM	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.24	4.65	0.167	0.183	
b	0.69	1.02	0.027	0.040	
b(1)	1.14	1.78	0.045	0.070	
С	0.36	0.61	0.014	0.024	
D	14.33	15.85	0.564	0.624	
Е	9.96	10.52	0.392	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.10	6.71	0.240	0.264	
J(1)	2.41	2.92	0.095	0.115	
L	13.36	14.40	0.526	0.567	
L(1)	3.33	4.04	0.131	0.159	
ØР	3.53	3.94	0.139	0.155	
Q	2.54	3.00	0.100	0.118	
ECN: X15- DWG: 603	0364-Rev. C, 1	14-Dec-15	1		

Note

- M^{\star} = 0.052 inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM



Disclaimer

All products due to improve reliability, function or design or for other reasons, product specifications and data are subject to change without notice.

Taiwan VBsemi Electronics Co., Ltd., branches, agents, employees, and all persons acting on its or their representatives (collectively, the "Taiwan VBsemi"), assumes no responsibility for any errors, inaccuracies or incomplete data contained in the table or any other any disclosure of any information related to the product.(www.VBsemi.com)

Taiwan VBsemi makes no guarantee, representation or warranty on the product for any particular purpose of any goods or continuous production. To the maximum extent permitted by applicable law on Taiwan VBsemi relinquished: (1) any application and all liability arising out of or use of any products; (2) any and all liability, including but not limited to special, consequential damages or incidental; (3) any and all implied warranties, including a particular purpose, non-infringement and merchantability guarantee.

Statement on certain types of applications are based on knowledge of the product is often used in a typical application of the general product VBsemi Taiwan demand that the Taiwan VBsemi of. Statement on whether the product is suitable for a particular application is non-binding. It is the customer's responsibility to verify specific product features in the products described in the specification is appropriate for use in a particular application. Parameter data sheets and technical specifications can be provided may vary depending on the application and performance over time. All operating parameters, including typical parameters must be made by customer's technical experts validated for each customer application. Product specifications do not expand or modify Taiwan VBsemi purchasing terms and conditions, including but not limited to warranty herein.

Unless expressly stated in writing, Taiwan VBsemi products are not intended for use in medical, life saving, or life sustaining applications or any other application. Wherein VBsemi product failure could lead to personal injury or death, use or sale of products used in Taiwan VBsemi such applications using client did not express their own risk. Contact your authorized Taiwan VBsemi people who are related to product design applications and other terms and conditions in writing.

The information provided in this document and the company's products without a license, express or implied, by estoppel or otherwise, to any intellectual property rights granted to the VBsemi act or document. Product names and trademarks referred to herein are trademarks of their respective representatives will be all.

Material Category Policy

Taiwan VBsemi Electronics Co., Ltd., hereby certify that all of the products are determined to be oHS compliant and meets the definition of restrictions under Directive of the European Parliament 2011/65 / EU, 2011 Nian. 6. 8 Ri Yue restrict the use of certain hazardous substances in electrical and electronic equipment (EEE) - modification, unless otherwise specified as inconsistent.(www.VBsemi.com)

Please note that some documents may still refer to Taiwan VBsemi RoHS Directive 2002/95 / EC. We confirm that all products identified as consistent with the Directive 2002/95 / EC European Directive 2011/65 /.

Taiwan VBsemi Electronics Co., Ltd. hereby certify that all of its products comply identified as halogen-free halogen-free standards required by the JEDEC JS709A. Please note that some Taiwanese VBsemi documents still refer to the definition of IEC 61249-2-21, and we are sure that all products conform to confirm compliance with IEC 61249-2-21 standard level JS709A.